Docket No.: 51876P340

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

SUNG Q LEE, ET AL.

Art Group:

Application No.:

Examiner:

Filed:

For:

NON-CONTACT SCANNING APPARATUS USING FREQUENCY RESPONSE

SEPARATION SCHEME AND SCANNING

METHOD THEREOF

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, enclosed is a copy of Information Disclosure Statement by Applicant (form PTO/SB/08), which is being submitted concurrently with the Utility Application. It is respectfully requested that the cited references be considered and that the enclosed copy of PTO/SB/08 be initialed by the Examiner to indicate such consideration and a copy thereof returned to applicant(s).

-1-

The submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made in the subject application and is not to be construed as an admission that the information cited in this statement is material to patentability.

Please charge any fees due to Deposit Account 02-2666. A duplicate copy of the Fee Transmittal (PTO/SB/17) is enclosed for this purpose.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Eric S. Hyman, Reg. No. 30,139

12400 Wilshire Blvd., 7th Floor Los Angeles, California 90025 (310) 207-3800

Date:

Substitute	for form 1449A/PTO			Co	Complete if Known		
			OUDE	Application Number			
INFORMATION DISCLOSURE				Filing Date			
STATEMENT BY APPLICANT				First Named Inventor	Sung Q LEE		
				Art Unit			
(use as many sheets as necessary)				Examiner Name			
Sheet	1	of	2	Attorney Docket Number	51876P340		

U.S. PATENT DOCUMENTS					
Examiner Initials* Cite No.1 Number - Kind Code² (if known)		Publication Date	Pages, Columns, Lines.		
		Number - Kind Code ² (if known)	or Iccus Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-6,094,971	08-01-2000	Edwards et al.	
		US-5,955,660	09-21-1999	Honma	
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		US-			

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	Cite	Foreign Patent Document	D. L. C. D. L.		Pages, Columns, Lines,	⊤ 6	
	No.1	Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	1	
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Examiner	Date
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¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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			OUDE	Application Number		
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STATEMENT BY APPLICANT (use as many sheets as necessary)				First Named Inventor	Sung Q LEE	
				Art Unit		
(use as many sneets as necessary)				Examiner Name		
Sheet	2	of	2	Attorney Docket Number	51876P340	

OTHER ART - NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²		
		J. THAYSEN et al., "Atomic Force Microscopy Probe Wheatstone Bridge Arrangement", SENSORS AND ACTUATORS 83(2000) (pp. 47-53)			
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		SUNG-Q LEE, et al., "Track/Focus Control and Fast Data Transfer Rate Data Storage Device", ASPE 2002 Annual Meeting, Vol. 27, pp. 176-181.			
		SUNG-Q LEE, et a., "Non-contact Type AFM Using Frequency Separation Scheme", ABSTRACT, pp375-378			

Examiner	•	Date	
Signature		Considered	

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